TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7SL00F, TC7SL00FU

2-INPUT NAND GATE

The TC7SL00 is a low voltage operative C²MOS 2-INPUT NAND GATE fabricated with silicon gate C²MOS technology.

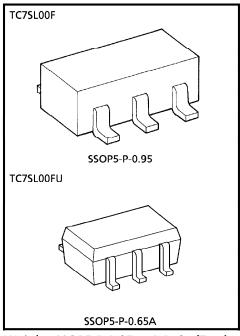
Operating voltage $(V_{CC(opr)})$ is 1~3V equivalent to 1pc or 2pcs of dry cell battery and it achives low power dissipation.

The internal circuit is composed of 3 stages including buffer output, which enables high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

FEATURES

- High Speed \cdots t_{pd} = 10ns (Typ.) at V_{CC} = 3V
- Low Power Dissipation $\cdots I_{CC} = 1\mu A$ (Max.) at $Ta = 25^{\circ}C$
- High Noise Immunity $V_{NIH} = V_{NIL}$ = 28% V_{CC} (Min.)
- Symmetrical Output Impedance ······ |I_{OH}| = I_{OL} = 1mA
- Balanced Propagation Delay Time ··· tpLH≒tpHL
- Low Voltage Operating·······V_{CC} (opr) = 1~3.6V

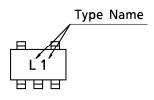


Weight SSOP5-P-0.95 : 0.016g (Typ.) SSOP5-P-0.65A : 0.006g (Typ.)

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	Vcc	-0.5~5	V
DC Input Voltage	VIN	-0.5~V _{CC} +0.5	V
DC Output Voltage	Vout	-0.5~V _{CC} +0.5	V
Input Diode Current	ΙΚ	± 20	mA
Output Diode Current	lok	± 20	mA
DC Output Current	IOUT	± 12.5	mA
DC V _{CC} / Ground Current	lcc	± 25	mA
Power Dissipation	PD	200	mW
Storage Temperature	T _{stg}	-65∼150	°C
Lead Temperature (10s)	TL	260	°C

MARKING



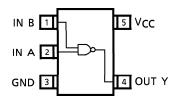
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LOGIC DIAGRAM

PIN CONNECTION (TOP VIEW)





RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	Vcc	1~3.6	V
Input Voltage	VIN	0~V _{CC}	٧
Output Voltage	Vout	0~V _{CC}	V
Operating Temperature	T _{opr}	- 40~85	°C
Input Rise and Fall Time		$0\sim 1000 (V_{CC} = 1.0V)$	
	t _r , t _f	0∼ 500 (V _{CC} = 1.5V)	ns
		0~ 400 (V _{CC} = 3.0V)	

DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC SYMBOL		TEST CIR-	TEST CONDITION		Ta = 25°C			Ta = −40~85°C		UNIT	
		CUIT			Vcc	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High Lovel Input					1.0	0.75	_	_	0.75	_	
High-Level Input V	VIH	_			1.5	1.05	_	—	1.05	_	V
					3.0	2.10	_	_	2.10	_	
Low-Level Input			_		1.0	—	_	0.25	_	0.25	
Voltage	V _{IL}	—			1.5	—	 	0.45	—	0.45	V
Voltage					3.0	_	_	0.90	_	0.90	
			V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20μA	1.0	0.9	1.0	<u> </u>	0.9	_	
High-Level					1.5	1.4	1.5	—	1.4	_	
Output Voltage	VOH	—			3.0	2.9	3.0	_	2.9	_	V
Output voltage				$I_{OH} = -1mA$	1.5	1.07	1.23	—	0.99		
				$I_{OH} = -2.6mA$	3.0	2.61	2.68	<u> </u>	2.55	_	
			V _{IN} = V _{IH}		1.0	l —	0.0	0.1	—	0.1	
Low-Level Output Voltage				$I_{OL} = 20 \mu A$	1.5	—	0.0	0.1	—	0.1	
	VOL	—			3.0	_	0.0	0.1	—	0.1	V
				$I_{OL} = 1mA$	1.5	—	0.23	0.31	—	0.37	
				$I_{OL} = 2.6 mA$	3.0	<u> </u>	0.23	0.31		0.33	
Input Leakage Current	IN	_	V _{IN} = V _{CC}	or GND	3.6	_		± 0.1	_	± 1.0	
Quiescent Supply Current	^l cc	_	$V_{IN} = V_{CC}$	or GND	3.6	_	_	1.0	_	10.0	μΑ

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 The information contained herein is subject to change without notice.

AC ELECTRICAL CHARACTERISTICS ($C_L = 15pF$, Input $t_r = t_f = 6ns$, $V_{CC} = 3.3 \pm 0.3 V$)

CHARACTERISTIC SYMBOL	TEST CIR- CUIT	TEST CONDITION		UNIT			
			MIN.	TYP.	MAX.	ONIT	
Output Transition	tTLH				5.0	9.0	ns
Time	tTHL	_	_	_	3.0	9.0	113
Propagation	t _{PLH}				7.5	13.0	ns
Delay Time	tpHL	-	_	_	/.5	13.0	113

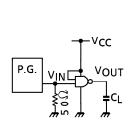
AC ELECTRICAL CHARACTERISTICS ($C_L = 25pF$, Input $t_r = t_f = 6ns$)

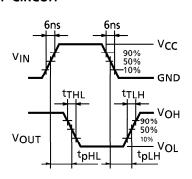
CHARACTERISTIC SYMBOL	CANADOL	TEST	TEST CONDITION 1		Ta = 25°C		Ta = -4			
	CIR- CUIT	1131 CONDITION	V_{CC}	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT	
Output Transition	4			1.0	_	70	170	_	240	
Output Transition Time	t _{TLH}	_	-	1.5	—	25	45	<u> </u>	55	ns
Time	tTHL			3.0	_	10	15		20	
Propagation	t n			1.0	_	70	170	_	210	
Propagation Delay Time	t _{PLH}	_	_	1.5	—	25	45	_	55	ns
Delay Time	t _{PHL}			3.0	_	10	15	_	20	
Input Capacitance	CIN	_	1		_	5	10		10	
Power Dissipation	Coo		Note (1)			10				рF
Capacitance	C _{PD}		Note (1)			10				

Note (1): CpD defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit).

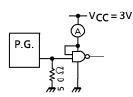
Average operating current can be obtained by the equation as follows. $I_{CC}(opr) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

SWITCHING CHARACTERISTICS TEST CIRCUIT





ICC (opr) TEST CIRCUIT

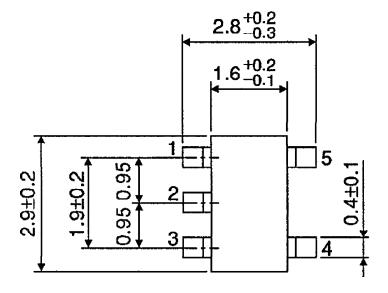


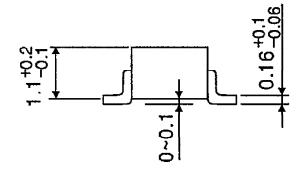
input waveform is the same as that in case of switching characteristics test.

OUTLINE DRAWING

SSOP5-P-0.95



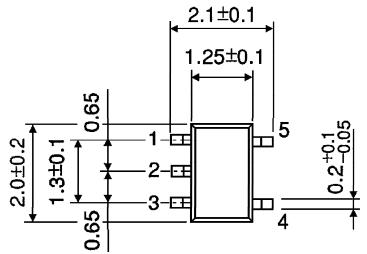




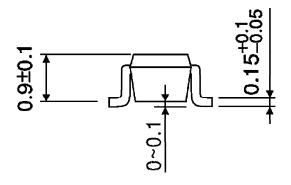
Weight: 0.016g (Typ.)

OUTLINE DRAWING

SSOP5-P-0.65A



Unit: mm



Weight: 0.006g (Typ.)